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CONFIRMATION NO. 1449

SERIAL NUMBER 10/585,995	FILING or 371(c) DATE 07/13/2006 RULE	CLASS 250	GROUP ART UNIT 2881	ATTORNEY DOCKET NO. 053848-5026		
APPLICANTS Erika Kanematsu, Chiba-ken, JAPAN; ** CONTINUING DATA ***** This application is a 371 of PCT/JP05/00625 01/13/2005 ** FOREIGN APPLICATIONS ***** JAPAN 2004-006422 01/14/2004 ** IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 04/06/2007						
Foreign Priority claimed <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No 35 USC 119(a-d) conditions met <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Verified and Acknowledged <u>/JACK I BERMAN/</u> Examiner's Signature		<input type="checkbox"/> Met after Allowance Initials	STATE OR COUNTRY JAPAN	SHEETS DRAWINGS 5	TOTAL CLAIMS 10	INDEPENDENT CLAIMS 4
ADDRESS MORGAN LEWIS & BOCKIUS LLP 1111 PENNSYLVANIA AVENUE NW WASHINGTON, DC 20004 UNITED STATES						
TITLE Projection electron microscope, electron microscope, specimen surface observing method and micro device producing method						
FILING FEE RECEIVED 1460	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit			